

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/698,892	TAM ET AL.	
Examiner	Art Unit	
Hiep Nguyen	2816	

	SEARCHED					
Class	Subclass	Date	Examiner			
327	198	07.13.0	4 1h			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
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